

Serial No. : 10/500,427
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IN THE ABSTRACT:

Please amend the abstract of the disclosure as follows:

An LSI test equipment can acquire output data of an LSI as a device under test by a clock signal output from the LSI to be measured and acquire measurement data synchronously with the output data having jitter. The LSI test equipment ~~(10)~~ includes a clock side time interpolator ~~(20)~~ for acquiring the clock output from the LSI ~~(1)~~ to be measured by a plurality of strobes having a predetermined timing interval and outputting it as encoded level data of time series, a data side time interpolator ~~(20)~~ for acquiring the output data ~~output~~ from the LSI ~~(1)~~ to be measured by a plurality of strobes having a predetermined timing interval and outputting it as level data of time series, and a selector ~~(30)~~ for receiving the level data from both of the time interpolators, selecting output data at the clock edge timing, and outputting it as data to be measured.